

Notice of References Cited	Application/Control No. 10/524,530	Applicant(s)/Patent Under Reexamination KOH ET AL.	
	Examiner Lei Yao, Ph.D.	Art Unit 1642	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0021597 A1	01-2007	Edwards et al.	536/023.2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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